

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/510,203	FIELDS ET AL.	
Examiner		Art Unit		Page 1 of 1
Ayal I Sharon		2123		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IEEE Standard Dictionary of Electrical and Electronics Terms. Dec. 1996. p.1098. "test bed", "test bench".
	V	
	W	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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